

<b>DATE :</b> Feb 2006	<b>QUALIFICATION REPORT</b>	<b>PAGE :</b> 1/2
	In accordance with PGQ 15 : <b>GENERAL PRINCIPLES OF QUALIFICATION</b>	

<i>Product :</i>	<b>AT84AD001B - DUAL 8 Bit 1 Gsps</b> <b>AT84AD004B - DUAL 8 Bit 500 Msps</b>
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<i>Qualification status :</i>	<input checked="" type="checkbox"/> <b>Accepted</b>	<input type="checkbox"/> <b>Pending</b>	<input type="checkbox"/> <b>Rejected</b>
<i>This product has met all ATMEL Grenoble qualification requirements.</i>			

<i>Qualified products :</i>	Package	Temperature range	Screening level
<b>AT84AD001BCTD</b>	<b>LQFP 144</b>	<b>“C” Grade : 0°C &lt; Ta &lt; 70°C</b>	<b>Standard</b>
<b>AT84AD001BITD</b>	<b>LQFP 144</b>	<b>“I” Grade : -40°C &lt; Ta &lt; 85°C</b>	<b>Standard</b>
<b>AT84AD004BCTD</b>	<b>LQFP 144</b>	<b>“C” Grade : 0°C &lt; Ta &lt; 70°C</b>	<b>Standard</b>
<b>AT84AD004BVTD</b>	<b>LQFP 144</b>	<b>“V” Grade : -40°C &lt; Ta &lt; 85°C</b>	<b>Standard</b>

<i>Directive 2002/95/EC compliance status :</i>	<input type="checkbox"/> <b>Pb free compliant</b>	<input type="checkbox"/> <b>RoHS compliant</b>	<input type="checkbox"/> <b>Fully Green compliant</b>
	<input checked="" type="checkbox"/> <b>Not compliant</b>		

<i>Die information :</i>		
Die size : <b>4.75 x 4.75 mm (22.56 mm<sup>2</sup>)</b>	P. dissipated in Watt : <b>0.12 to 1.85 W</b>	Mask : <b>VK99F &amp; VL69A</b>
Wafer fab. : <b>ATMEL (Rousset)</b>	Process : <b>AT43K</b>	Technology : <b>BiCMOS 0.4 µm</b>

<i>Package information :</i>		
Outline : <b>20 x 20 x 1.4 mm</b>	Pitch : <b>0.5 mm</b>	Lead Finition : <b>Sn/Pb 63/37</b>
Assy plant : <b>ASAT (HK)</b>	Moisture sensitivity level : <b>MSL 3</b>	Max. peak reflow : <b>225°C</b>

<i>Approbation list :</i>			
Project Eng.	Product Eng.	BDC Quality	BDC Marketing
NICOLAS J-A.	BELLEFET J.	CARMONA C.	TERRIEN JC.

<b>DATE :</b> May 2005	<b>QUALIFICATION REPORT</b>	<b>PAGE :</b> 2/2
	In accordance with PGQ 15 : <b>GENERAL PRINCIPLES OF QUALIFICATION</b>	

<i>Product :</i>	<b>AT84AD001B - DUAL 8 Bit 1 Gbps</b> <b>AT84AD004B - DUAL 8 Bit 500 Mbps</b>
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<i>Qualification batch information :</i>			
Mask : <b>VK99C</b>	Diffusion lot : <b>3R3399</b>	Lot ID : <b>1661363</b>	Date Code : <b>0345</b>

<i>Qualification tests results :</i>						
SUB-GROUP	TEST <i>Acceptable criteria</i>	METHOD <i>Condition</i>	LTPD or Qty (Acc. Nb)	Sample	Acc. Numb.	Fail
-	<i>Pre-acousting microscopy</i> <b>THERMAL PRE-COND. L3</b> <i>Post-acousting microscopy</i> <i>Electrical measurements</i> <i>Visual inspection</i>	J-STD-020-C (peak 225°C)  <i>J-STD-035</i> <i>Ambient T°</i> <i>MIL STD-883 TM 2009</i>	150 (0)	150	0	0
D3	<b>TEMPERATURE CYCLING *</b>  <i>Electrical measurements</i> <i>Visual inspection</i>	MIL STD-883 TM 1010 -65°C to 150°C / 1000 cy.  <i>Ambient T°</i> <i>MIL STD-883 TM 2009</i>	50 (0)	50	0	0
-	<b>PRESSURE COOKER *</b>  <i>Electrical measurements</i> <i>Visual inspection</i>	JESD22-A102-B 121°C/100% RH/2atm/168H  <i>Ambient T°</i> <i>MIL STD-883 TM 2009</i>	50 (0)	50	0	0
-	<b>THB *</b>  <i>Electrical measurements</i> <i>Visual inspection</i>	JESD22-A101 85°C / 85% RH / 500H  <i>Ambient T°</i> <i>MIL STD-883 TM 2009</i>	50 (0)	50	0	0
-	<b>ESD</b> <i>Electrical measurements</i>	MIL-STD 883 / 3015 750V HBM	3 (0)	3	0	0
-	<b>Latch-Up</b> <i>Electrical measurements</i>	JEDEC 78  <i>Class 2</i>	3 (0)	3	0	0
C1	<b>Steady-state life test</b> <i>Electrical measurements</i>	MIL-STD 883 / 1005 <i>Tj 125°C / 2000H</i>	45 (0)	45	0	0

*Observations :* \* Devices issued from thermal pre-conditioning level 3